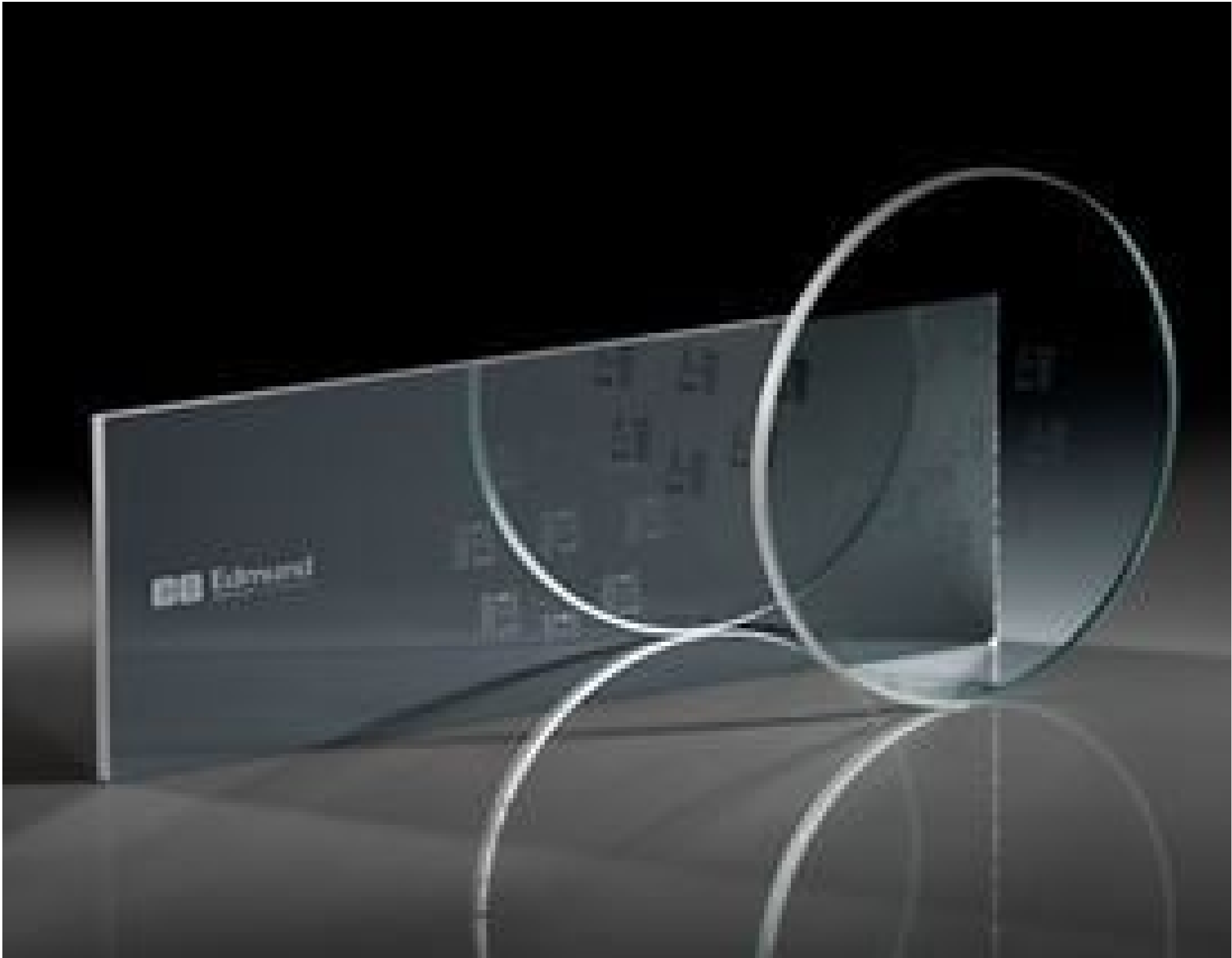
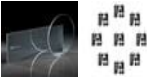


1.5" Dia. Negative, USAF Wheel Target



USAF Pattern Wheel Targets



Stock **#59-207** CLEARANCE **5 In Stock**

-

1

+

€379^{.04}

ADD TO CART

Volume Pricing	
Qty 1-4	€379,04 each
Qty 5+	€360,60 each
Need More?	Request Quote

i Prices shown are exclusive of VAT/local taxes

Product Downloads

SPECIFICATIONS

Physical & Mechanical Properties

Thickness (mm):

1.50	
<0.0005 per inch	Parallelism (inches):
±0.0005	Line Width Tolerance (mm):
Optical Properties	
First Surface Reflective Chromium	Coating:
Float Glass	Substrate:
Minimum: Group 2 Element 1 Maximum: Group 7 Element 6	Resolution:
20-10	Surface Quality:
2λ	Surface Flatness (P-V):
Regulatory Compliance	
Compliant	RoHS 2015:
View	Certificate of Conformance:
Compliant	Reach 240:

PRODUCT DETAILS

- Tests Resolutions from 4 to 228 lp/mm
- Ability to tests Multiple Field Points using 9 Targets
- Reduces Testing Time

The USAF pattern wheel is an ideal target to measure resolution at different field points within an imaging system's field of view. The pattern is available on three different substrate sizes: 1" square, 1.5" diameter, or a 1" x 3" slide. Each size includes 8 USAF patterns in a circular pattern plus one pattern in the center. Each size is offered as positive (opaque pattern on clear background) or negative (clear pattern on opaque background).

TECHNICAL INFORMATION

Element	Group No.					
	2	3	4	5	6	7
1	4.00	8.00	16.00	32.0	64.0	128.0
2	4.49	8.98	17.95	36.0	71.8	144.0
3	5.04	10.10	20.16	40.3	80.6	161.0
4	5.66	11.30	22.62	45.3	90.5	181.0
5	6.35	12.70	25.39	50.8	102.0	203.0
6	7.13	14.30	28.50	57.0	114.0	228.0